

ELECTROMAGNETIC COMPLIANCE TEST REPORT

For

Photo Dynamic Therapy System

Model: BL001, BL002, BL003, BL004, BL005, BL006, BL007, BL008, BL009, BL010, BL020, BL030, BL040, BL050

Brand Name: SUSLASER

Report No.: ENC170523GZ40E1

Date of Issue: Jun 1, 2017

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1. VERIFICATION OF CONFORMITY

Equipment Under Test:	Photo Dynamic Therapy System			
Model:	BL001, BL002, BL003, BL004, BL005, BL006, BL007, BL008, BL009 BL010, BL020, BL030, BL040, BL050			
Model Difference:	All models have same electrical structure as BL001, except for the different appearance and power.			
Brand Name:	SUSLASER			
Applicant:	SUS Advancing Technology Co., LTD			
	3/F, #6 Jiahe Wanggang Luduan, West Jichang Road, Baiyun District Guangzhou 510440			
Manufacturer:	SUS Advancing Technology Co., LTD			
	3/F, #6 Jiahe Wanggang Luduan, West Jichang Road, Baiyun District, Guangzhou 510440			
Type of Test:	EMC Directive 2014/30/EU for CE Marking			
Technical Standards:	EN 55014-1:2006+A1:2009+A2:2011 EN 61000-3-2:2014 EN 61000-3-3:2013 EN 55014-2:2015 (IEC 61000-4-2:2008; IEC 61000-4-3:2010; IEC 61000-4-4:2012; IEC 61000-4-5:2014; IEC 61000-4-6:2013; IEC 61000-4-11:2004)			
File Number:	ENC170523GZ40E1			
Date of test:	May 23, 2017 – Jun 1, 2017			
Deviation:	None			
Condition of Test Sample:	Normal			

The above equipment was tested by East Notice Certification Service Co., Ltd. for compliance with the requirements set forth in EMC Directive 2014/30/EU and the Technical Standards mentioned above. This said equipment in the configuration described in this report shows the maximum emission levels emanating from equipment and the level of the immunity endurance of the equipment are within the compliance requirements. Should any objections to the test reports occurred, should submit it to the Company within ten days since the issuing of the report, Fail to accept.

The test results of this report relate only to the tested Sample identified in this report.

Checked By

Authorized By

Ray Zhou Jun 1

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2. SYSTEM DESCRIPTION

EUT Test Procedure:

- 1. Connect EUT and peripheral devices if need.
- 2. Power on the EUT, the EUT begins to work.
- 3. Make sure the EUT operates normally during the test.

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3. PRODUCT INFORMATION

Housing Type : Plastic & Metal 220-240V~, 50Hz **Rated Voltage**

Rated Power 150W **Protection Class** Class I

□Not Applicable) I/O Port Information (⊠Applicable

I/O Port of EUT				
I/O Port Type	Q'TY	Cable	Tested with	
AC Input port	1 🕏	1.5 m unshielded	* 41 4	

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Device Type	Manufacturer	Model Name	Serial No.	Data Cable	Power Cable
Q	- i	-C	- A	- ·	0

**Note: All the above equipment/cables were placed in worse case positions to maximize emission signals during emission test.

Grounding: Grounding was in accordance with the manufacturer's requirements and conditions for the intended use.

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Location: 1/F, Haohui Commercial Building, Zhuji Street, Dongpu Town, Tianhe District,

Guangzhou City, China

Description: There is one 3m semi-anechoic an area test sites and two line conducted labs for

final test. The Open Area Test Sites and the Line Conducted labs are constructed and calibrated to meet the FCC requirements in documents ANSI C63.4 and CISPR

14/EN 55014 requirements.

Site Filing: The site description is on file with the Federal Communications Commission, 7435

Oakland Mills Road, Columbia, MD 21046.

Instrument Tolerance: All measuring equipment is in accord with ANSI C63.4 and CISPR 14 requirements

that meet industry regulatory agency and accreditation agency requirement.



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6. EN 55014 LINE CONDUCTED EMISSION TEST

6.1. TEST EQUIPMENT OF CONDUCTED EMISSION TEST

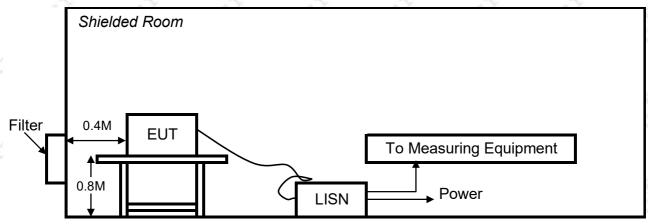
Description	Manufacturer	Model	Identifier	Cal. Date	Cal. Due
Spectrum Analyzer	Aeroflex	2399A	N/A	03/20/2017	03/19/2018
LISN	HAMEG	HM6050-2	N/A	03/20/2017	03/19/2018

6.2. LIMITS OF LINE CONDUCTED EMISSION TEST

Evenuency	Maximum RF Line Voltage			
Frequency	Q.P.(dBuV)	Average(dBuV)		
150kHz-500kHz	66-56	56-46		
500kHz-5MHz	56	46		
5MHz-30MHz	60	50		

^{**}Note: 1. The lower limit shall apply at the transition frequency.

6.3. BLOCK DIAGRAM OF TEST SETUP



A:Powered through filter

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^{2.} The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.50 MHz



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6.4. PROCEDURE OF LINE CONDUCTED EMISSION TEST

- The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per EN55014 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- Support equipment, if needed, was placed as per EN55014
- 3) All I/O cables were positioned to simulate typical actual usage as per EN55014
- 4) The EUT received AC230V/50Hz power through a Line Impedance Stabilization Network (LISN) which supplied power source and was grounded to the ground plane.
- 5) All support equipments received power from a second LISN supplying power of AC 230V/50Hz, if any.
- The EUT test program was started. Emissions were measured on each current carrying line of the EUT using a spectrum Analyzer / Receiver connected to the LISN powering the EUT. The LISN has two monitoring points: Line 1 (Hot Side) and Line 2 (Neutral Side). Two scans were taken: one with Line 1 connected to Analyzer / Receiver and Line 2 connected to a 50 ohm load; the second scan had Line 1 connected to a 50 ohm load and Line 2 connected to the Analyzer / Receiver.
- Analyzer / Receiver scanned from 150 kHz to 30 MHz for emissions in each of the test modes.
- 8) During the above scans, the emissions were maximized by cable manipulation.
- 9) A scan was taken on both power lines, Line 1 and Line 2, recording at least the six highest emissions.
- 10) Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. If EUT emission level was less -2dB to the A.V. limit in Peak mode, then the emission signal was re-checked using Q.P and Average

The test data of the worst case condition(s) was reported on the Summary Data page.

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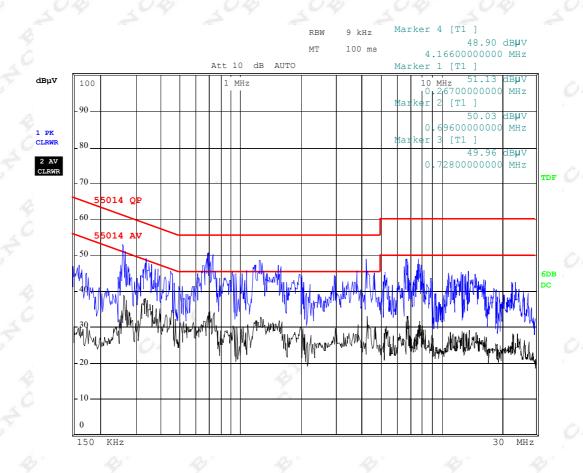
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6.5. TEST RESULT OF LINE CONDUCTED EMISSION TEST

Mode : Normal, L Humidity : 50%



RESULT: PASS

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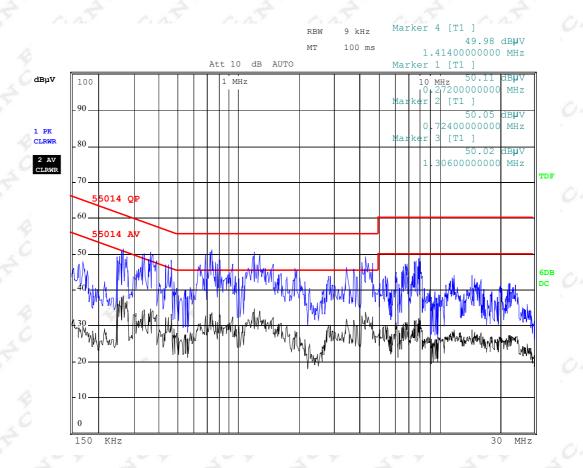
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EUT Power AC230V Photo Dynamic Therapy System

M/N 25℃ **Temperature** BL001 **Humidity** Mode Normal, N 50%



RESULT: PASS

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7. EN55014 DISTURBANCE POWER EMISSION TEST

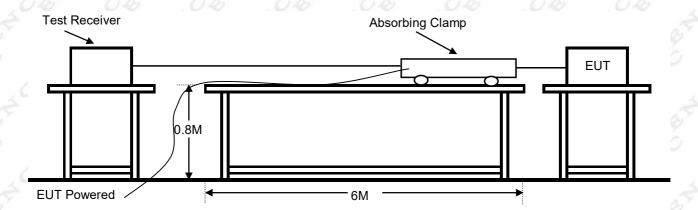
7.1. TEST EQUIPMENT OF DISTURBANCE POWER EMISSION TEST

Description	Manufacturer	Model	Identifier	Cal. Date	Cal. Due
Test Receiver	R&S	CISPR16	N/A	03/20/2017	03/19/2018
Absorbing Clamp	CSI	CLA-050	N/A	03/20/2017	03/19/2018
Cable	TS	TS®90	N/A	03/20/2017	03/19/2018

7.2. LIMITS OF DISTURBANCE POWER EMISSION TEST

Equipment Type	e Frequency (MHz)	Limit Values dB(pW)		
		Quasi-peak	Average	
Associated equipment	30-300	45-55	35-45	
2000 20	Increasing linearly with	n the frequency	14 204	

7.3. BLOCK DIAGRAM OF TEST SETUP



Note:

EUT is placed on a non-metallic table of 0.1 m of height above the floor and at least 0.8m from other metallic objects and from any person. The lead to be measured shall be stretched in a straight horizontal line for length sufficient to accommodated the absorbing clamp.

The absorbing clamp is placed around the lead to be measured, with its current transformer towards the equipment under test.

All connectors not used shall be left un-terminated. All connectors having a connected lead shall be terminated in a manner representative of use.

The absorbing clamp is applied successively to all leads whose length is 25cm or longer, unscreened or screened, which may be connected to the individual units of the equipment under test.

At each test frequency the absorbing clamp shall be moved along the lead until the maximum value is found between a position adjacent to the equipment under test and a distance of about a half wavelength from it.

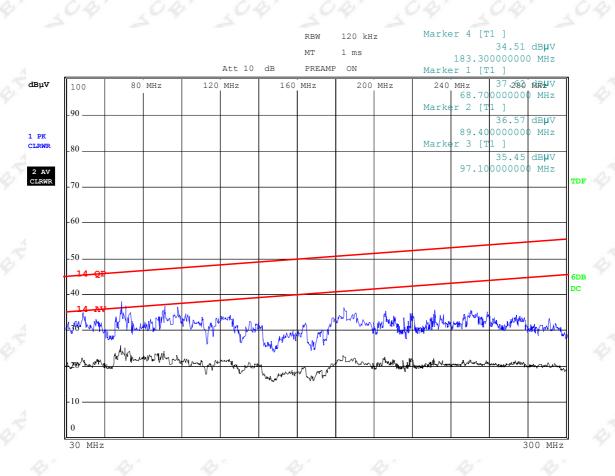
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7.4. SUMMARY DATA OF DISTURBANCE POWER EMISSION TEST

EUT AC230V **Power** Photo Dynamic Therapy System **25**℃ M/N **Temperature** BL001 Humidity 50% Mode Normal



RESULT: PASS



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8. EN 61000-3-2 POWER HARMONICS TEST

POWER HARMONICS MEASUREMENT

Port : AC mains

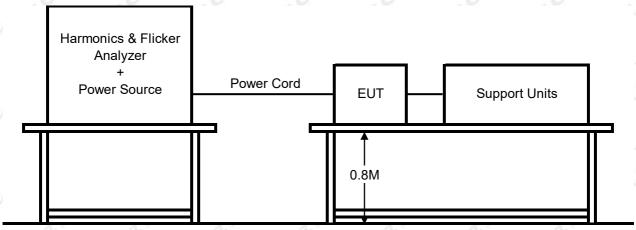
Basic Standard : EN 61000-3-2:2014

Limits: CLASS ATester: Sam LiuTemperature: 25° CHumidity: 50%

8.1. TEST EQUIPMENT OF POWER HARMONICS TEST

Description	Manufacturer	Model	Identifier	Cal. Date	Cal. Due
Harmonic Emission Flicker	California instruments	500LIX-400	N/A	03/20/2017	03/19/2018

8.2. BLOCK DIAGRAM OF TEST SETUP



Note:

- 1. The EUT was tested with the equipment configured to its rated current.
- 2. The measurements were carried out under steady conditions. When a piece of EUT is brought into operation or is taken out of operation, manually or automatically, harmonic currents and power are not taken into account at first 10s following the switching event. EUT shall not be in standby mode for more than 10% of any observation period.
- 3. Harmonics of the fundamental current were measured using a digital power meter with an analogue output and frequency analyser which was integrated in the harmonic & flicker test system.
- 4. For each harmonic order, measure the 1,5 s smoothed r.m.s. harmonic current in each DFT time window and calculate the arithmetic average of the measured values from the DFT time windows, over the entire observation period. Each harmonic order, all 1.5 s smoothed r.m.s. harmonic current values and the average values for the individual harmonic currents, taken over the entire test observation period shall be less than or equal to the applicable limits.

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8.3. LIMITS OF HARMONIC CURRENT

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Limits for 0	Class A Equipment
Harmonics Order n	Max. permissible harmonic current (A)
OO Odd	harmonics O
10,5 00,5 30,05 00,5	2.3
-5	1.14
4 4 7 4 T	0.77
30 30 3	0.40
14 04 104 04	() (A) () () () () () () () () () () () () ()
13	0.21
15≤n≤39	0.15×15/n
Eve	n harmonics
14 04 204 04	04 04 1.0804 04
4	0.43
6 6 6	0.30
8≤n≤40	0.23×8/n

NOTE:

- According to section 5 of EN 61000-3-2: 2014, the EUT is Class A equipment.
- The above limits are for all applications having an active input power>75W. No limits apply for equipment with an active input power up to and including 75W.

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8.4. RESULT

Test Specification

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Test Frequency:	50Hz	Test Voltage:	230Vac
Waveform:	Sine	Test Time:	2.5min
Classification:	Class A	Test result:	PASS

Harmonic current results

~	- Y	~~	~ ~	
Hn	Harms(max) [A]	Limit [%]	Limit[A]	Result
5×1	0.775	000 0	000	005
2	0.018	1.709	1.080	PASS
3	0.119	5.160	2.300	PASS
3 4 5	0.015	3.573	0.430	PASS
5	0.070	6.118	1.140	PASS
6	0.014	4.649	0.300	PASS
7	0.061	7.943	0.770	PASS
8	0.011	4.815	0.230	PASS
9	0.018	4.554	0.400	PASS
10	0.009	4.682	0.184	PASS
11	0.008	2.449	0.330	PASS
12	0.006	4.021	0.153	PASS
13	0.006	2.801	0.210	PASS
14	0.005	3.757	0.131	PASS
15	0.006	3.796	0.150	PASS
16	0.003	3.004	0.115	PASS
17	0.004	3.029	0.132	PASS
18	0.003	2.719	0.102	PASS
19	0.003	2.740	0.118	PASS
20	0.002	2.503	0.092	PASS
21	0.003	2.746	0.107	PASS
22	0.002	2.742	0.084	PASS
23	0.003	2.669	0.098	PASS
24	0.001	1.496	0.077	PASS
25	0.003	2.865	0.090	PASS
26	0.001	1.622	0.071	PASS
27	0.002	2.421	0.083	PASS
28	0.001	1.745	0.066	PASS
29	0.002	2.953	0.078	PASS
30	0.000	0.000	0.061	PASS
31	0.002	3.155	0.073	PASS
32	0.000	0.000	0.058	PASS
33	0.001	1.694	0.068	PASS
34	0.000	0.000	0.054	PASS
35	0.001	1.799	0.064	PASS
36	0.000	0.000	0.051	PASS
37	0.000	0.000	0.061	PASS
38	0.000	0.000	0.048	PASS
39	0.000	0.000	0.058	PASS
40	0.000	0.000	0.046	PASS

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9. EN 61000-3-3 VOLTAGE FLUCTUATION / FLICKER TEST

VOLTAGE FLUCTUATION/FLICKER MEASUREMENT

Port : AC mains

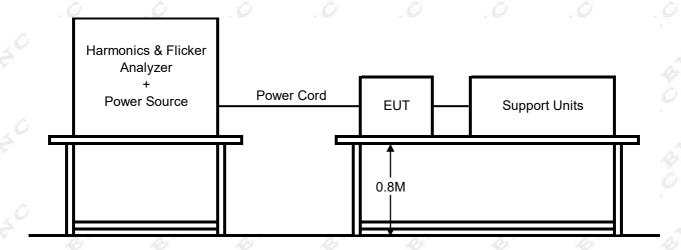
Basic Standard : EN 61000-3-3:2013 **Limits** : §5 of EN 61000-3-3

Tester: Sam LiuTemperature: 25° CHumidity: 50%

9.1. TEST EQUIPMENT OF VOLTAGE FLUCTUATION / FLICKER TEST

Description	Manufacturer	Model	Identifier	Cal. Date	Cal. Due
Harmonic Emission Flicker	California instruments	500LIX-400	N/A	03/20/2017	03/19/2018

9.2. BLOCK DIAGRAM OF TEST SETUP



- 1. The test supply voltage (open-circuit voltage) was the rated voltage of the EUT. The test voltage was maintained within ±2 % of the nominal value. The frequency was 50 Hz ±0.5 %.
- 2. The voltage fluctuations and flicker were measured at the supply terminals of the EUT.
- The observation period, Tp, for the assessment of flicker values by flicker measurement, flicker simulation, or analytical method was:
 - for Pst, Tp = 10 min;
 - for Plt, Tp = 2 h.

The observation period included that part of the whole operation cycle in which the EUT produces the most unfavourable sequence of voltage changes.

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9.3. RESULT

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Flicker Test Summary per EN/IEC61000-3-3 (Run time)

EUT: Photo Dynamic Therapy System Tested by: Sam Liu

Test category: All parameters (European limits)

Test Margin: 100

Test date: 2017-05-24

Start time: 15:45:10

End time: 15:55:10

Test duration (min): 10

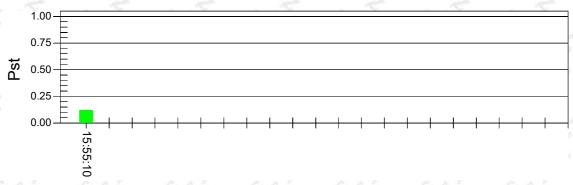
Comment: On

Customer: SUS Advancing Technology Co., LTD

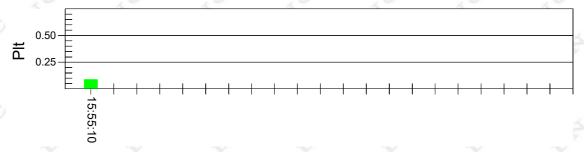
Test Result: Pass Source qualification: OK

Pst and limit line

European Limits



Plt and limit line



Parameter values recorded during the test:

Vrms at the end of test (Volt): 230.1

Highest dt(%):	-0.26	Test limit (%):	3.30	Pass
Time(mS) > dt:	0.0	Test limit (mS):	500.0	Pass
Highest dc (%):	0.00	Test limit (%):	3.30	Pass
Highest dmax (%):	-0.16	Test limit (%):	4.00	Pass
Highest Pst (10 min. period):	0.116	Test limit:	1.000	Pass
Highest Plt (2 hr. period):	0.092	Test limit:	0.650	Pass

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10. IEC 61000-4-2 ESD IMMUNITY TEST

ELECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST

Port : Enclosure

Basic Standard : IEC 61000-4-2:2008
Test Level : ±8 kV (Air Discharge)

±4 kV (Contact Discharge) ±4 kV (Indirect Discharge)

Standard require : B

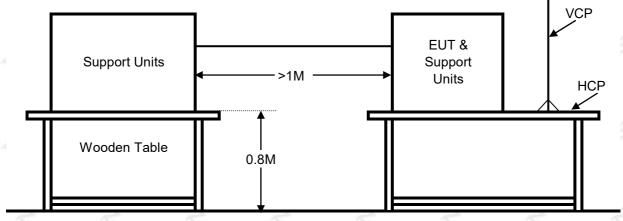
Tester: Sam LiuTemperature: 25° CHumidity: 50%

10.1. TEST EQUIPMENT OF ESD TEST

Description	Manufacturer	Model	Identifier	Cal. Date	Cal. Due
ESD Simulator	EM-Test	EST883	N/A	03/20/2017	03/19/2018

10.2. BLOCK DIAGRAM OF TEST SETUP

(The 470 k ohm resistors are installed per standard requirement)



Ground Reference Plane

10.3. TEST PROCEDURE

The EUT was located 0.1 m minimum from all side of the HCP.

The support units were located 1 m minimum away from the EUT.

EUT worked with resistance load, and make sure EUT worked normally.

Actives the communication function if the EUT with such port(s).

As per the requirement of EN 55014: Contact discharge is the preferred test method. 20 discharges (10 with positive and 10 negative polarity) shall be applied on each accessible metal part of the enclosure. In case of a non-conductive enclosure, discharges shall be applied on the horizontal or vertical coupling planes as specified in IEC 61000-4-2.

Air discharges shall be used where contact discharges cannot be applied.

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The following test condition was followed during the tests.

Note: As per the A2 to IEC 61000-4-2, a bleed resistor cable is connected between the EUT and HCP during the test.

The electrostatic discharges were applied as follows:

Amount of Discharges	Voltage	Coupling	Result (Pass/Fail)		
Mini 20 /Point	±2kV; ±4kV	Contact Discharge	Pass		
Mini 10 /Point	±2kV; ±4kV	Indirect Discharge HCP (Front)	Pass		
Mini 10 /Point	±2kV; ±4kV	Indirect Discharge VCP (Left)	Pass		
Mini 10 /Point	±2kV; ±4kV	Indirect Discharge VCP (Back)	Pass		
Mini 10 /Point	±2kV; ±4kV	Indirect Discharge VCP (Right)	Pass		
Mini 10 /Point	±2kV; ±4kV;±8kV;	Air Discharge	Pass		

10.4. PERFORMANCE & RESULT

East Notice Certification

A 100 A	
☐ Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of
	function is allowed below a performance level specified by the manufacturer, when the
	apparatus is used as intended. In some cases the performance level may be replaced by a
	permissible loss of performance.
⊠Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance
	or loss of function is allowed below a performance level specified by the manufacturer, when

the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.

□Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or car	ı be
	restored by the operation of controls.	

20 Y	20 Y	26 Y	a Y	A. Y	A. Y	20 Y	20
		⊠ PAS	S	□ FAIL			·



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11. IEC 61000-4-3 TEST

RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST

Port : Enclosure

Basic Standard : IEC 61000-4-3:2010

Test Level : 3V/m with 80% AM. 1kHz Modulation.

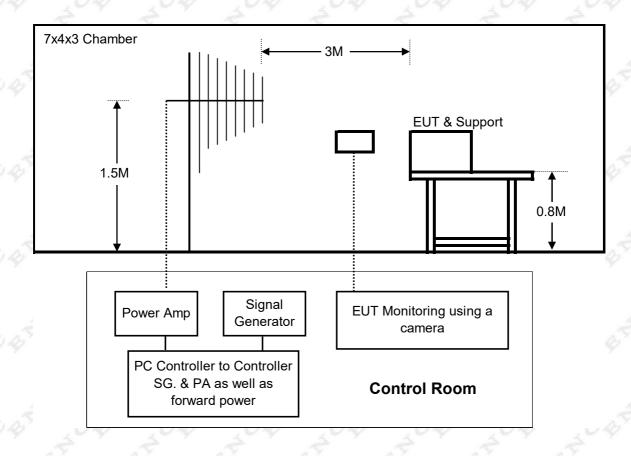
Standard require : A

Tester: Sam LiuTemperature: 25° CHumidity: 50%

11.1. TEST EQUIPMENT

Description	Manufacturer	Model	Identifier	Cal. Date	Cal. Due
Signal Generator	IFA	2023B	N/A	03/20/2017	03/19/2018
Power Amplifier	AR	150W1000	N/A	03/20/2017	03/19/2018
Power Antenna	AR	25S1G4A	N/A	03/20/2017	03/19/2018

11.2. BLOCK DIAGRAM OF TEST SETUP



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11.3. TEST PROCEDURE

The EUT was located at the edge of supporting table keep 3 meter away from transmitting antenna, it just the calibrated square area of field uniformity. The support units were located outside of the uniformity area, but the cable(s) connected with EUT were exposed to the calibrated field as per IEC 61000-4-3.

EUT worked with resistance load, and make sure EUT worked normally.

Setting the testing parameters of RS test software per IEC 61000-4-3.

Performing the test at each side of with specified level (3V/m) at 1% steps and test frequency from 80MHz to 1000MHz and 1400MHz to 2700MHz.

Recording the test result in following table.

It is not necessary to perform test as per annex A of EN 55014 if the EUT doesn't belong to TTE product.

IEC 61000-4-3 Final test conditions:

Test level: 3V/m

Steps: 1 % of fundamental

Dwell Time : 1 sec

Range (MHz)	Field	Modulation	Polarity	Position	Result (Pass/Fail)
80-1000	3V/m	AM	н	Front	Pass
80-1000	3V/m	AM	O PH	Left	Pass
80-1000	3V/m	AM AM	Н	Back	Pass
80-1000	3V/m	Ó AM	но	Right	Pass
80-1000	3V/m	AM	V	Front	Pass
80-1000	3V/m	AM	V	Left	Pass
80-1000	3V/m	AM A	V 49	Back	Pass
80-1000	3V/m	O AM	V.O	Right	Pass

11.4. PERFORMANCE & RESULT

□Criteria B: The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.

☐ Criteria C: Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

		⊠ PASS	□ FAIL		

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12. IEC 61000-4-4 TEST

ELECTRICAL FAST TRANSIENTS/BURST IMMUNITY TEST

Port : On Power Supply Lines
Basic Standard : IEC 61000-4-4:2012

Test Level : +/- 1kV for Power Supply Lines

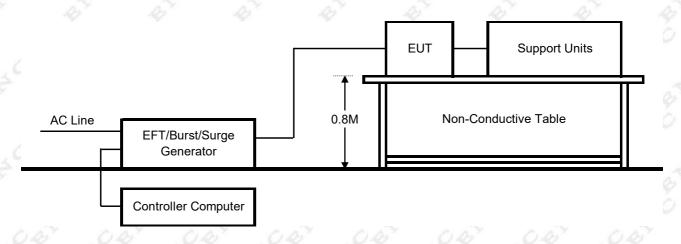
Standard require : B

Tester : Sam Liu
Temperature : 25°C
Humidity : 50%

12.1. TEST EQUIPMENT

Description	Manufacturer	Model	Identifier	Cal. Date	Cal. Due
Compact Generator	EM-Test	UCS500M	N/A	03/20/2017	03/19/2018
Capacitive Clamp	EM-Test	HY21-EFTC	N/A	03/20/2017	03/19/2018
CDN for Telecom Port	EM-Test	CNV504S1	O N/A	03/20/2017	03/19/2018

12.2. BLOCK DIAGRAM OF TEST SETUP



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12.3. TEST PROCEDURE

The EUT and support units were located on a wooden table 0.8m away from ground reference plane.

A 1.0 meter long power cord was attached to EUT during the test.

The length of communication cable between communication port and clamp was keeping within 1 meter.

EUT worked with resistance load, and make sure EUT worked normally.

Related peripherals work during the test.

Recording the test result as shown in following table.

Test conditions:

Impulse Frequency: 5 kHz

Tr/Th: 5/50ns

Burst Duration: 15ms Burst Period: 300ms

Inject Line	Voltage kV	Inject Method	Result (Pass/Fail)	
L+N	+ /- 1	Direct	Pass	

12.4. PERFORMANCE & RESULT

- □Criteria A: The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ⊠Criteria B: The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- □Criteria C: Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

		PASS	□ <i>FAIL</i>		
	IXI	<i>ra</i> ss	FAIL		
	_		-		

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13. IEC 61000-4-5 SURGE IMMUNITY TEST

SURGE IMMUNITY TEST

Port : On Power Supply Lines
Basic Standard : IEC 61000-4-5:2014
Requirements : +/- 1kV (Line to Line)

+/- 2kV (Line to Ground)

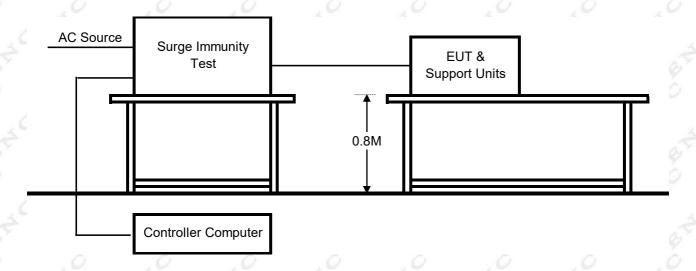
Standard require : B

Tester: Sam LiuTemperature: 25° CHumidity: 50%

13.1. TEST EQUIPMENT OF SURGE TEST

Description	Manufacturer	Model	Identifier	Cal. Date	Cal. Due
Compact Generator	EM-Test	UCS500M	N/A	03/20/2017	03/19/2018
Capacitive Clamp	EM-Test	HY21-EFTC	N/A	03/20/2017	03/19/2018
CDN for Telecom Port	EM-Test	CNV504S1	N/A	03/20/2017	03/19/2018

13.2. BLOCK DIAGRAM OF TEST SETUP



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13.3. TEST PROCEDURE

The EUT and support units were located on a wooden table 0.8 m away from ground floor.

EUT worked with resistance load, and make sure EUT worked normally.

Recording the test result as shown in following table.

Test conditions:

Voltage Waveform : 1.2/50 us Current Waveform : 8/20 us

Polarity : Positive/Negative Phase angle : 0°, 90°, 270°

Number of Test : 5

Coupling Line Voltage (kV)		Polarity	Coupling Method	Result (Pass/Fail)
2 🔷 L1-L2 🗸 🔷	2019	Positive	Capacitive	Pass
L1-L2	5 1 5	Negative	Capacitive	Pass
L1-PE	2	Positive	Capacitive	Pass
L1-PE	2	Negative	Capacitive	Pass
L2-PE	2	Positive	Capacitive	Pass
L2-PE	2	Negative	Capacitive	Pass

13.4. PERFORMANCE & RESULT

- □Criteria A: The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐Criteria C: Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

	PASS	□ FAIL		

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14. IEC 61000-4-6 TEST

IEC 61000-4-6 IMMUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY

FIELD

Port : Power Supply Lines

Basic Standard : IEC 61000-4-6:2013

Requirements : 3V with 80% AM. 1 kHz Modulation

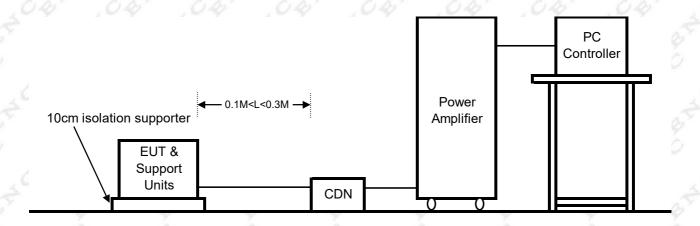
Standard require : A

Tester : Sam Liu
Temperature : 25°C
Humidity : 50%

14.1. TEST EQUIPMENT

Manufacturer	Model	Identifier	Cal. Date	Cal. Due	
AR AR	150W1000	N/A	03/20/2017	03/19/2018	
EM-Test	CNV504S1	N/A	03/20/2017	03/19/2018	
EM-Test	DC2600N	O N/A	03/20/2017	03/19/2018	
EM-Test	EM101	N/A	03/20/2017	03/19/2018	
EM-Test	CAM2/M3	N/A	03/20/2017	03/19/2018	
EM-Test	ATT6/75	N/A	03/20/2017	03/19/2018	
AR	PH2000	O N/A	03/20/2017	03/19/2018	
AR	PM2002	N/A	03/20/2017	03/19/2018	
IFA	2023A	N/A	03/20/2017	03/19/2018	
	AR EM-Test EM-Test EM-Test EM-Test EM-Test AR AR	AR 150W1000 EM-Test CNV504S1 EM-Test DC2600N EM-Test EM101 EM-Test CAM2/M3 EM-Test ATT6/75 AR PH2000 AR PM2002	AR 150W1000 N/A EM-Test CNV504S1 N/A EM-Test DC2600N N/A EM-Test EM101 N/A EM-Test CAM2/M3 N/A EM-Test ATT6/75 N/A AR PH2000 N/A AR PM2002 N/A	AR 150W1000 N/A 03/20/2017 EM-Test CNV504S1 N/A 03/20/2017 EM-Test DC2600N N/A 03/20/2017 EM-Test EM101 N/A 03/20/2017 EM-Test CAM2/M3 N/A 03/20/2017 EM-Test ATT6/75 N/A 03/20/2017 AR PH2000 N/A 03/20/2017 AR PM2002 N/A 03/20/2017	

14.2. BLOCK DIAGRAM OF TEST SETUP



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14.3. TEST PROCEDURE

The EUT and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.

EUT worked with resistance load, and make sure EUT worked normally.

Related peripherals work during the test.

Setting the testing parameters of CS test software per IEC 61000-4-6.

Recording the test result in following table.

Test conditions:

Frequency Range: 0.15MHz-230MHz
Frequency Step: 1% of fundamental

Dwell Time: 1 sec

Range (MHz)	Strength	Modulation	Result (Pass/Fail)	
0.15-230	3V	AM	Pass	

14.4. PERFORMANCE & RESULT

⊠Criteria A:	The apparatus continues to opera	te as intended. No	o degradation of p	performance or I	oss of
	function is allowed below a perf	ormance level sp	ecified by the m	anufacturer, whe	n the
	apparatus is used as intended. In	some cases the p	performance level	may be replaced	d by a
	permissible loss of performance.				

□Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or
	loss of function is allowed below a performance level specified by the manufacturer, when the
	apparatus is used as intended. In some cases the performance level may be replaced by a
	permissible loss of performance. During the test, degradation of performance is however
	allowed.

□Criteria C:	Temporary loss of function is allowed	, provided the	functions self	recoverable or	can be restored
	by the operation of controls.				

 	 	3	-	 13.
	PASS	□ FAIL		

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15. IEC 61000-4-11 TEST

VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST

Port : Power Supply Lines

Basic Standard : IEC 61000-4-11:2004

Requirements : 0, 45, 90, 135, 180, 225, 270, 315 degrees

Standard require: Min. 10 sec.Test Interval:: Sam LiuTemperature: 25°CHumidity: 50%

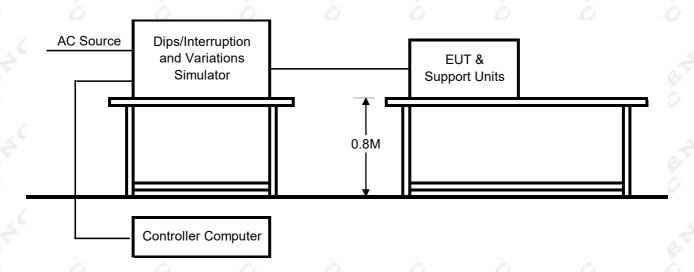
	Test Level	Reduction	Duration	Performance	
Valtana Dina	% U _T	(%)	(periods)	Criteria	
Voltage Dips	40	60	10	C	
	70 4	0 <30	25 0 49	C 49	

Voltage Interruptions	Test Level	Reduction	Duration	Performance
	% U _T	(%)	(periods)	Criteria
	0	100	0.5	С

15.1. TEST EQUIPMENT

		A STATE OF THE PARTY OF T			
Description	Manufacturer	Model	Identifier	Cal. Date	Cal. Due
Compact Generator	EM-Test	UCS500M	N/A	03/20/2017	03/19/2018
Capacitive Clamp	EM-Test	HY21-EFTC	N/A	03/20/2017	03/19/2018
CDN for Telecom Port	EM-Test	CNV504S1	N/A	03/20/2017	03/19/2018

15.2. BLOCK DIAGRAM OF TEST SETUP



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15.3. TEST PROCEDURE

The EUT and support units were located on a wooden table, 0.8 m away from ground floor. EUT worked with resistance load, and make sure EUT worked normally.

Setting the parameter of tests and then perform the test software of test simulator.

Conditions changes to occur at 0 degree crossover point of the voltage waveform.

Recording the test result in test record form.

Test conditions:

The duration with a sequence of three dips/interruptions with interval of 10 s minimum (Between each test event)

Voltage Dips:

Test Level % U _⊤	Reduction (%)	Duration (periods)	Observation	Meet Performance Criteria
40	60	10	Normal	C
70	0 30	25	Normal	,Cc

Voltage Interruptions:

Test Level	Reduction	Duration	Observation	Meet Performance	
% U _T	(%)	(periods)		Criteria	
0 0	100	0.5	Normal	C	

15.4. PERFORMANCE

- ☐Criteria A: The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- □Criteria B: The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.

~ 4	3 0 .A.	, V Y	, V Y	2 ~ .A	, V Y	, V Y	, V Y
			⊠ <i>PASS</i>		FAIL		

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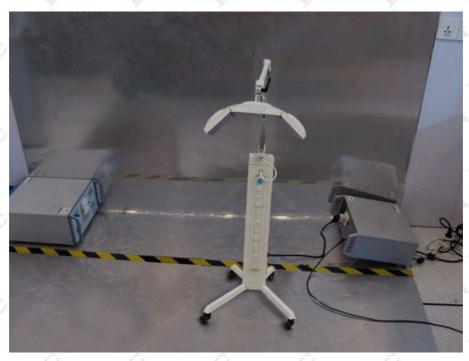




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APPENDIX 1 PHOTOGRAPHS OF TEST SETUP

CONDUCTED EMISSION TEST SETUP

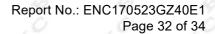


EN 61000-3-2 POWER HARMONICS & EN 61000-3-3 VOLTAGE FLUCTUATION/FLICKER TEST SETUP



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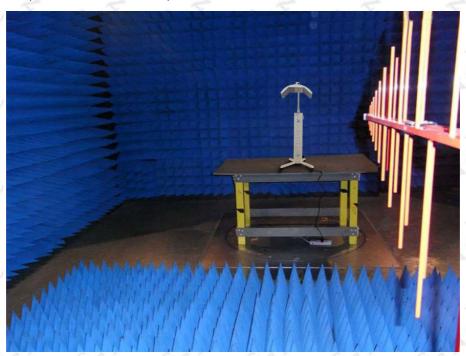




ELECTROSTATIC DISCHARGE TEST SETUP



RADIATED, RADIO-FREQUENCY, ELECTROMAGNETIC FIELD IMMUNITY TEST SETUP



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APPENDIX 2 PHOTOGRAPHS OF EUT

FRONT VIEW OF EUT



BACK VIEW OF EUT



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SIDE VIEW OF EUT



INTERNAL VIEW OF EUT



---END OF REPORT----

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